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***For Immediate Release***

**Akrometrix Announces 30 Year Anniversary as the Industry Leader in Thermal Warpage Metrology**

Akrometrix, LLC - Atlanta, Georgia - Professor Ifeanyi Charles Ume founded Akrometrix out of Georgia Tech 30 years ago, to address issues in PCB flatness, using the shadow moiré warpage measurement technique.

These early concepts evolved into industry standards for measuring applications within the semiconductor industry, most often while samples were subject to temperature changes. Akrometrix would go on to add additional metrology techniques in Digital Fringe Projection (DFP), as a complimentary warpage technology to shadow moiré, and Digital Image Correlation (DIC), to address the need for surface strain measurements.

Currently Akrometrix systems remain the industry leading technology for thermal warpage and strain metrology. Akrometrix techniques are utilized across the world by the leaders of the microelectronics industry managing quality assurance, NPI, and failure analysis of surface mount devices.

For more information about Akrometrix, email [equipmentsales@akrometrix.com](mailto:equipmentsales@akrometrix.com) or go to [www.akrometrix.com](http://www.akrometrix.com).